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Page(s): 793 -801[\[Abstract\]](#) [\[PDF Full-Text \(716 KB\)\]](#) **IEEE CNF****2 Guardbanding VLSI EEPROM test programs***Sweetman, D.;*
VLSI Test Symposium, 1991. 'Chip-to-System Test Concerns for the 90's', Digest of Papers , 15-17 April 1991
Page(s): 155 -160[\[Abstract\]](#) [\[PDF Full-Text \(376 KB\)\]](#) **IEEE CNF****3 Side fringing fields and write and read crosstalk of narrow magnetic recording heads***van Herk, A.;*
Magnetics, IEEE Transactions on , Volume: 13 Issue: 4 , Jul 1977
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3 Statistical circuit modeling and optimization
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4 A practical methodology for the statistical design of complex logic products for performance
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5 Toward a practical methodology for the statistical design of complex integrated circuit products
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6 An interchange format for process and device simulation
Duvall, S.G.;

Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on , Volume: 7 Issue: 7 , July 1988

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1 Quantitative characterization of substrate noise for physical design guides in digital circuits
Nagata, M.; Nagai, J.; Morie, T.; Iwata, A.;
Custom Integrated Circuits Conference, 2000. CICC. Proceedings of the IEEE 2000 , 21-24 May 2000
Page(s): 95 -98

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Williams, R.H.; Hawkins, C.F.;
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Bezalel Gavish, Joakim Kalvenes

February 1998

Wireless Networks, Volume 4 Issue 2Full text available:  pdf (650.86 KB)Additional Information: [full citation](#), [abstract](#), [references](#), [index terms](#)

Low earth orbit satellite (LEOS) systems promise to provide global communication, including voice and data services from Iridium and high capacity broadband services from Teledesic. In design of LEOS systems, the choice of satellite altitude is an important consideration, which has a significant impact on system performance. Among the factors affected by satellite altitude choice are system capacity, user-to-user delay, power system design and communication services that can be offered. Thi ...

2 System design methodology of ultraSPARC-I

Lawrence Yang, David Gao, Jamshid Mostoufi, Raju Joshi, Paul Loewenstein

January 1995

Proceedings of the 32nd ACM/IEEE conference on Design automation conferenceFull text available:  pdf (57.00 KB)Additional Information: [full citation](#), [references](#), [citing](#), [index terms](#)**3 A protocol for efficient transfer of data over hybrid fiber/coax systems**

John O. Limb, Dolors Sala

December 1997

IEEE/ACM Transactions on Networking (TON), Volume 5 Issue 6Full text available:  pdf (168.35 KB)Additional Information: [full citation](#), [references](#), [index terms](#), [review](#)**Keywords:** HFC, MAC protocol, cable TV, cable modem, residential broad-band access

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1 Fast detection of communication patterns in distributed executions

Thomas Kunz, Michiel F. H. Seuren

November 1997

Proceedings of the 1997 conference of the Centre for Advanced Studies on Collaborative research

Full text available: pdf(4.21 MB)

Additional Information: [full citation](#), [abstract](#), [references](#), [index terms](#)

Understanding distributed applications is a tedious and difficult task. Visualizations based on process-time diagrams are often used to obtain a better understanding of the execution of the application. The visualization tool we use is Poet, an event tracer developed at the University of Waterloo. However, these diagrams are often very complex and do not provide the user with the desired overview of the application. In our experience, such tools display repeated occurrences of non-trivial commun ...

2 Pen computing: a technology overview and a vision

André Meyer

July 1995

ACM SIGCHI Bulletin, Volume 27 Issue 3

Full text available: pdf(5.14 MB)

Additional Information: [full citation](#), [abstract](#), [clings](#), [index terms](#)

This work gives an overview of a new technology that is attracting growing interest in public as well as in the computer industry itself. The visible difference from other technologies is in the use of a pen or pencil as the primary means of interaction between a user and a machine, picking up the familiar pen and paper interface metaphor. From this follows a set of consequences that will be analyzed and put into context with other emerging technologies and visions. Starting with a short historic ...

3 Selection criteria for expert system shells: a socio-technical framework

Anthony C. Stylianou, Gregory R. Madey, Robert D. Smith

October 1992

Communications of the ACM, Volume 35 Issue 10

Full text available: pdf(20.75 MB)

Additional Information: [full citation](#), [references](#), [clings](#), [index terms](#), [review](#)

Keywords: expert system development tools, expert system shells, software evaluation criteria, software selection

4 NSF workshop on industrial/academic cooperation in database systems

Mike Carey, Len Seligman

March 1999

ACM SIGMOD Record, Volume 28 Issue 1

Full text available: pdf(1.99 MB)

Additional Information: [full citation](#), [index terms](#)

5 Technological advances in software engineering

A. N. Habermann

February 1986

Proceedings of the 1986 ACM fourteenth annual conference on Computer science

Full text available: pdf(1.95 MB)

Additional Information: [full citation](#), [references](#)

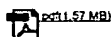
6 Charles Welty

January 1984

Proceedings of the ACM 12th annual computer science conference on SIGSE symposium

Full text available:

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[full citation](#), [index terms](#)

⁷ [The Anti-Mac interface](#)

Don Gentner, Jakob Nielsen

August 1996 **Communications of the ACM**, Volume 39 Issue 8

Full text available: pdf (2.39 MB)

Additional Information: [full citation](#), [references](#), [citations](#), [index terms](#), [review](#)

⁸ [Sequential patterns in information systems development: an application of a social process model](#)

Daniel Robey, Michael Newman

January 1996 **ACM Transactions on Information Systems (TOIS)**, Volume 14 Issue 1

Full text available: pdf (2.39 MB)

Additional Information: [full citation](#), [abstract](#), [references](#), [citations](#), [index terms](#), [review](#)

We trace the process of developing and implementing a materials management system in one company over a 15-year period. Using a process research model developed by Newman and Robey, we identify 44 events in the process and define them as either encounters or episodes. Encounters are concentrated events, such as meetings and announcements, that separate episodes, which are events of longer duration. By examining the sequence of events over the 15 years of the case, we identify a pattern of r ...

Keywords: social processes, system implementation

⁹ [A pattern matching algorithm for verification and analysis of very large IC layouts](#)

Mariusz Niewczas, Wojciech Maly, Andrzej Strojwas

April 1998 **Proceedings of the 1998 international symposium on Physical design**

Full text available: pdf (922.92 KB)

Additional Information: [full citation](#), [abstract](#), [references](#), [citations](#), [index terms](#)

We propose a simple, isometry invariant pattern matching algorithm for an effective data reduction useful in layout-related data processing of very complex IC designs. The repeatable geometrical features and attributes are stored in a pattern database. Original pattern instance, or its geometrical attributes, may be quickly regenerated based both on the information stored within the pattern and position of the pattern instance. We also show preliminary results of analysis of the state-of-th ...

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[Unive1ks lty - Of Technology Division](#) (Correct)

22 subcarriers (4.17 kHz each) 2 subcarrier **guardband** Transmission block 7 kHz each QPSK pilot symbol OFDM symbols. Each transmission block has 1 empty **guardband** carrier on either side. We will refer to such www.sm.luth.se/csee/sp/research/conference/Synch_of_TDMA-OFDM.pdf

[Simulation Study of ABR Service . . . - Golmie, al. \(1997\)](#) (Correct)

to gathering statistics 10% of simulated time **Guardband** and pre-amble between transmissions from www.eecs.umich.edu/~mcorner/papers/97-011.pdf

[Target Prescreening Based on 2D Gamma Kernels - Principe, Radisavljevic, Kim, ..](#) (Correct)

2a) because it determines the size of the **guardband**. Little attention has been given to the width The gamma kernel can adaptively set both the **guardband** and the width of the neighborhood as we will stencil (left) and combined gamma kernel **Guardband** Test cell (a) b) $x \ 2 \ 0 \ 2x \ 0 \ x \ -x \ 2 \ T$ www.cnel.ufl.edu/bib/pdf_papers/principe95spie.pdf

[Hierarchical Cell Structures for FRAMES Wideband Wireless.. - Robert Karlsson Jens \(1996\)](#) (Correct)

channel plan definitions of carrier spacing and **guardband** width (example $N=10$) Handoff procedures is micro/macro cell bands, may be kept unused as a **guardband** (at a capacity penalty) Fig 1 illustrates the www.s3.kth.se/radio/Publication/Pub1996/RobertSKarlsson1996_1.pdf

[Congestion Control in Mobile Networks - Subramanian, Dahlberg \(2000\)](#) (Correct)

congestion which calls for an increase in the **guardband**, while decreasing fr rt implies the in the AAC 1 #plane indicate cells for which the **guardband** has been increased due to bursts during the www.cs.uncc.edu/~krs/publications/2000/infovis_lbht.pdf

[Performance of Contention Resolution Algorithms using . . . - Sala, al. \(1997\)](#) (Correct)

to Gathering Statistics 5% of simulated time **Guardband**, pre-amble and PHY/MAC headers. 16 bytes Ratio www.cc.gatech.edu/fac/John.Limb/papers/IEEE97-048.ps

[On Quality of Service in an ATM-based HFC Architecture - Nichols, Laubach \(1996\)](#) (Correct)

1 byte of management information, plus FEC and **guardband** bytes. The head-end controls the upstream www.aciri.org/floyd/cbq/scbq.pdf

[A Bayesian Approach To Object Detection In Sidescan Sonar - Calder, Linnett, Carmichael](#) (Correct)

The main H Object neighbourhood Background **guardband** Shadow neighbourhood t h S N y B N y O N www.cee.hw.ac.uk/iarg/papers/iee-ipa97-obj.ps.gz

[Performance Evaluation of a New Photonic ATM Switching.. - Gabriagues Masetti](#) (Correct)

shown that such a device can cope with a 2-bit **guardband** with a negligible penalty [8]3. EXPERIMENTAL www.elec.uow.edu.au/conferences/95-149.ps

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